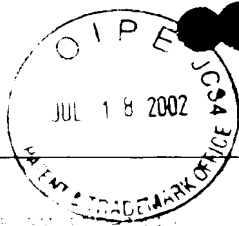


EXAMINER	10/10
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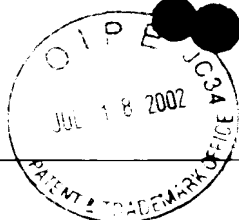
U.S. PATENT AND TRADEMARK OFFICE WASHINGTON, D.C. 20590	INVENTOR'S NAME Last, first, middle initial	INVENTOR'S ADDRESS Street, city, state, zip
	ATTORNEY'S NAME Firm name	
	EXAMINER'S NAME Last, first, middle initial	DATE Month, day, year

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	NAME	TYPE	FILED	REMARKS
	AA						
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	TYPE	FILED	REMARKS
8/12	AL	W. 100,000,000	1/1/1999	USA			See
	AM	W. 100,000,000	1/1/1999	USA			See
	AN	W. 100,000,000	1/1/1999	USA			See
	AO						See
	AP						See

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
8/12	1		1. A method of determining the age of a person by measuring the ratio of the concentration of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair, and comparing the ratio to a known ratio of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair at the time of the person's death.
1	2		2. A method of determining the age of a person by measuring the ratio of the concentration of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair, and comparing the ratio to a known ratio of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair at the time of the person's death.
4	3		3. A method of determining the age of a person by measuring the ratio of the concentration of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair, and comparing the ratio to a known ratio of the isotope ^{14}C to the concentration of the isotope ^{12}C in a sample of the person's hair at the time of the person's death.

EXAMINER'S NAME Last, first, middle initial	DATE Month, day, year
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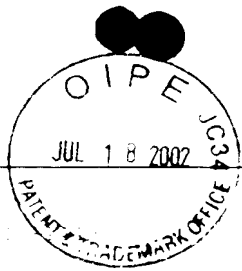
PATENT & TRADEMARK OFFICE JUL 18 2002	INVENTOR Name and Address	ATTORNEY Name and Address
	TITLE Name and Address	
	EXAMINER Name and Address	DATE Month and Year

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	REF- DATE	EXAMINER DATE
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FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	REF- DATE	TRANSLATION
	AL						Yes N
	AM						Yes N
	AN						Yes N
	AO						Yes N
	AP						Yes N

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
FILE	AB	-	Examination of the application for a patent for the invention of a "Method for the production of a new type of paper" by the American Paper Company, Inc., New York, N.Y., U.S.A., dated July 18, 2002.
		-	Examination of the application for a patent for the invention of a "Method for the production of a new type of paper" by the American Paper Company, Inc., New York, N.Y., U.S.A., dated July 18, 2002.
		-	Examination of the application for a patent for the invention of a "Method for the production of a new type of paper" by the American Paper Company, Inc., New York, N.Y., U.S.A., dated July 18, 2002.

EXAMINER:	DATE:
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EXAMINER'S OFFICE JUL 18 2002 PATENT & TRADEMARK OFFICE	INVENTOR'S NAME	INVENTOR'S ADDRESS
	TITLE OF INVENTION	
	CLASSIFICATION	CLASSIFICATION

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		U.S. PATENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	TRANSLATION
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FOREIGN PATENT DOCUMENTS							
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	AL						
	AM						
	AN						
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	AP						
	AQ						

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
1	2	3	4

EXAMINER'S SIGNATURE	DATE
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EXAMINER'S STATEMENT <u>NO SMALL ENTITY FEE STATEMENT</u>	CLASSIFICATION CLASS. NO. & EXT. CL.	CLASSIFICATION CLASS. NO. & EXT. CL.
	ATTORNEY NAME & FIRM	
	EXAMINER NAME & FIRM	DATE FILED

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	CLASS	CLASS	CLASS	EXAMINER DATE
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FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	CLASS	CLASS	CLASS	TRANSLATION
	AL						Yes No
	AM						Yes No
	AN						Yes No
	AO						Yes No
	AP						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
100	AB	-	Examiner's Statement: "The invention is directed to a method of determining the relative positions of two points in a three-dimensional space. The method involves determining the relative positions of two points in a two-dimensional space, and then determining the relative positions of the two points in a three-dimensional space. The method is described in detail in the accompanying drawings and the accompanying text."
	AC	-	Examiner's Statement: "The invention is directed to a method of determining the relative positions of two points in a three-dimensional space. The method involves determining the relative positions of two points in a two-dimensional space, and then determining the relative positions of the two points in a three-dimensional space. The method is described in detail in the accompanying drawings and the accompanying text."
100	AD	-	Examiner's Statement: "The invention is directed to a method of determining the relative positions of two points in a three-dimensional space. The method involves determining the relative positions of two points in a two-dimensional space, and then determining the relative positions of the two points in a three-dimensional space. The method is described in detail in the accompanying drawings and the accompanying text."

EXAMINER'S SIGNATURE 100	DATE 100
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EXAMINER'S REPORT THE EXAMINER'S REPORT MUST BE FORWARDED TO THE EXAMINER	APPLICANT'S NAME JAMES H. BROWN	APPLICANT'S ADDRESS 1234 MAIN ST. ANYTOWN, CA 94501
	ATTORNEY'S NAME JAMES H. BROWN	
	EXAMINER'S NAME JAMES H. BROWN	EXAMINER'S ADDRESS 1234 MAIN ST. ANYTOWN, CA 94501

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	NAME	TYPE	FILED IN	FILED DATE
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	TYPE	FILED IN	FILED DATE
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	AM						1998-01-01
	AN						1998-01-01
	AO						1998-01-01
	AP						1998-01-01

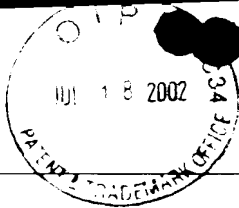
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
3878	AB	-	James H. Brown, Jr., "A Method for Determining the Optimal Position of a Rotating Object," U.S. Pat. No. 5,678,901, 1998-01-01, 1-10.
	AC	-	James H. Brown, Jr., "A Method for Determining the Optimal Position of a Rotating Object," U.S. Pat. No. 5,678,901, 1998-01-01, 11-15.
	AD	-	James H. Brown, Jr., "A Method for Determining the Optimal Position of a Rotating Object," U.S. Pat. No. 5,678,901, 1998-01-01, 16-20.

EXAMINER'S SIGNATURE JAMES H. BROWN	EXAMINER'S ADDRESS 1234 MAIN ST. ANYTOWN, CA 94501
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U.S. PATENT DOCUMENTSFOREIGN PATENT DOCUMENTS

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER



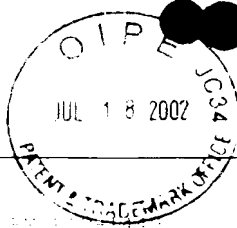
U.S. PATENT AND TRADEMARK OFFICE PATENT EXAMINATION UNIT	INVENTOR	DATE OF INVENTION
	TITLE	
	CLASSIFICATION	CLASSIFICATION

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		U.S. PATENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	EXAMINER
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FOREIGN PATENT DOCUMENTS							
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	AM						No
	AN						No
	AO						No
	AP						No
	AQ						No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
100	AB	1	1. A method of... 2. A device for... 3. A system for...
		2	4. A method of... 5. A device for... 6. A system for...
		3	7. A method of... 8. A device for... 9. A system for...

EXAMINER:	
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THE EXAMINER'S INITIAL STATEMENT	DATE OF EXAMINATION	10/1/01
	EXAMINER	DAVID M. HARRIS
	EXAMINER'S NAME	DAVID M. HARRIS

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		SEQUENCE NUMBER	DATE	COUNTRY	CLASS	FILED CLASS	FILED DATE
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EXAMINER INITIAL		SEQUENCE NUMBER	DATE	COUNTRY	CLASS	FILED CLASS	FILED DATE
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	AM						10/1/01
	AN						10/1/01
	AO						10/1/01
	AP						10/1/01
	AL						10/1/01

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
10/1/01	AA	—	Initial Applicant's "Information Statement" dated 10/1/01, which sets forth the applicant's understanding of the prior art and the applicant's position with respect to the prior art.
10/1/01	AP	—	Initial Applicant's "Information Statement" dated 10/1/01, which sets forth the applicant's understanding of the prior art and the applicant's position with respect to the prior art.
10/1/01	AT	—	Initial Applicant's "Information Statement" dated 10/1/01, which sets forth the applicant's understanding of the prior art and the applicant's position with respect to the prior art.

EXAMINER:	DAVID M. HARRIS	DATE:	10/1/01
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NAME OF INVENTOR ADDRESS OF INVENTOR CITY AND STATE AND ZIP CODE	INVENTOR'S SIGNATURE	DATE
	ATTORNEY Firm Name Address	
	EXAMINER'S NAME	DATE

U.S. PATENT DOCUMENTS

EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	TOPIC CLASS	TRANSLATION
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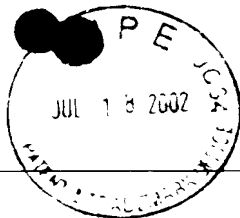
FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	TOPIC CLASS	TRANSLATION
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	AM						Yes
	AN						Yes
	AO						Yes
	AP						Yes

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

CCC	AD	—	See, also, "The"
		—
		—

EXAMINER:



U.S. PATENT & TRADEMARK OFFICE WASHINGTON, D.C. 20590	INVENTOR Name and address	ATTORNEY Name and address
	APPLICANT Name and address	
	TITLE Inventor's name	DATE Month, day, year

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	OFF- CLASS	FILED DATE
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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	OFF- CLASS	TRANSLATION
	AL						Yes
	AM						Yes
	AN						Yes
	AO						Yes
	AP						Yes
	AQ						Yes

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

801K	20	—	U.S. Pat. No. 4,111,711, "Method of determining the relative humidity of a gas mixture by measuring the change in the refractive index of the gas mixture as a function of the relative humidity of the gas mixture."
	21	—	U.S. Pat. No. 4,111,712, "Method of determining the relative humidity of a gas mixture by measuring the change in the refractive index of the gas mixture as a function of the relative humidity of the gas mixture."
	22	—	U.S. Pat. No. 4,111,713, "Method of determining the relative humidity of a gas mixture by measuring the change in the refractive index of the gas mixture as a function of the relative humidity of the gas mixture."

EXAMINER



OFFICE OF THE COMMISSIONER OF PATENTS WASHINGTON, D.C. 20503 JUL 18 2002	INVENTOR'S NAME Last, first, and middle initial	APPLICANT'S NAME Last, first, and middle initial
	ATTORNEY Last, first, and middle initial	
	EXAMINER'S NAME Last, first, and middle initial	DATE Month, day, and year

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	OFF. FILED	FILED IN
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FOREIGN PATENT DOCUMENTS							
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	AM						Yes No
	AN						Yes No
	AO						Yes No
	AP						Yes No
	AQ						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
502	AP	1	Examiner's note: This document is a continuation of the application of the same inventor, filed in the U.S. Patent Office on July 18, 2002, and is hereby incorporated by reference.
		2	Examiner's note: This document is a continuation of the application of the same inventor, filed in the U.S. Patent Office on July 18, 2002, and is hereby incorporated by reference.
		3	Examiner's note: This document is a continuation of the application of the same inventor, filed in the U.S. Patent Office on July 18, 2002, and is hereby incorporated by reference.

EXAMINER'S SIGNATURE	DATE
EXAMINER'S NAME	DATE



I HEREBY CERTIFY THAT THE STATEMENTS MADE BY ME IN THIS APPLICATION ARE TRUE TO THE BEST OF MY KNOWLEDGE AND BELIEF.	INVENTOR'S NAME [Blank]	DATE OF INVENTION [Blank]
	ATTORNEY [Blank]	
	EXAMINER'S NAME [Blank]	DATE [Blank]

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		U.S. PATENT NUMBER	DATE	NAME	CLASS	OFF. CLASS	EXAMINER'S NAME
	AA						
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIAL		U.S. PATENT NUMBER	DATE	COUNTRY	CLASS	OFF. CLASS	EXAMINER'S NAME
	AL						AL
	AM						AM
	AN						AN
	AO						AO
	AP						AP

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
176	AP	—	U.S. Pat. No. 1,760,000, "Method of and Apparatus for Treating Paper," issued May 19, 1929.
	AP	—	U.S. Pat. No. 1,760,000, "Method of and Apparatus for Treating Paper," issued May 19, 1929.
	AP	—	U.S. Pat. No. 1,760,000, "Method of and Apparatus for Treating Paper," issued May 19, 1929.

EXAMINER'S NAME [Blank]	DATE [Blank]
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P. 1711-1111 THE EXAMINER'S INITIAL AND STATEMENT	Applicant's Name [Name]	Applicant's Address [Address]
	Applicant's City/State/Zip [City/State/Zip]	
	Examiner's Name [Name]	Examiner's Address [Address]

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	YEAR	REF. DATE	EXAMINER'S NAME
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	YEAR	REF. DATE	EXAMINER'S NAME
	AL						Y- N
	AM						Y- N
	AN						Y- N
	AO						Y- N
	AP						Y- N

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
2002	1	—	1. The present invention relates to a method of determining the degree of similarity between two documents. The method involves comparing the documents on a word-by-word basis and determining the percentage of words that are identical. The method is particularly useful for determining the degree of similarity between two documents that are written in different languages.
	2	—	2. The present invention relates to a method of determining the degree of similarity between two documents. The method involves comparing the documents on a word-by-word basis and determining the percentage of words that are identical. The method is particularly useful for determining the degree of similarity between two documents that are written in different languages.
	3	—	3. The present invention relates to a method of determining the degree of similarity between two documents. The method involves comparing the documents on a word-by-word basis and determining the percentage of words that are identical. The method is particularly useful for determining the degree of similarity between two documents that are written in different languages.

EXAMINER: [Name]	DATE: [Date]
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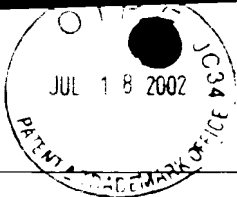
EXAMINER'S STATEMENT	APPLICANT'S NAME	INVENTOR'S NAME
	ATTORNEY'S NAME	
	EXAMINER'S NAME	DATE

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TOP-CLASS	EXAMINER'S DATE
	AA						
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FOREIGN PATENT DOCUMENTS							
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	AM						Y-1
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	AO						Y-1
	AP						Y-1
	AQ						Y-1

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
Y-1	Y-1	Y-1	Author, Title, Date, Pertinent Pages, etc.
Y-1	Y-1	Y-1	Author, Title, Date, Pertinent Pages, etc.
Y-1	Y-1	Y-1	Author, Title, Date, Pertinent Pages, etc.

EXAMINER'S SIGNATURE	DATE
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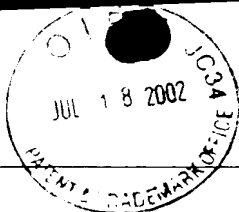
U.S. PATENT OFFICE THE APPLICANT'S STATEMENT	INVENTOR'S NAME	INVENTOR'S ADDRESS
	ATTORNEY'S NAME	
	ATTORNEY'S ADDRESS	DATE

U.S. PATENT DOCUMENTS							
EXAMINER'S INITIAL		U.S. PATENT NUMBER	DATE	CASE	CLASS	CLASS	EXAMINER'S NAME
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FOREIGN PATENT DOCUMENTS							
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	AL						AL
	AM						AM
	AN						AN
	AO						AO
	AP						AP
	AQ						AQ

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
7/1/02	AA	---	1. A method for determining the "best" of a set of data, comprising the steps of: (a) receiving a set of data; (b) determining the "best" of the set of data; and (c) outputting the "best" of the set of data.
	AB	---	2. A method for determining the "best" of a set of data, comprising the steps of: (a) receiving a set of data; (b) determining the "best" of the set of data; and (c) outputting the "best" of the set of data.
	AC	---	3. A method for determining the "best" of a set of data, comprising the steps of: (a) receiving a set of data; (b) determining the "best" of the set of data; and (c) outputting the "best" of the set of data.

EXAMINER	
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OFFICE OF THE PATENT AND TRADEMARK COMMISSIONER WASHINGTON, D.C. 20503	INVENTOR'S NAME Last, first, and middle initial	INVENTOR'S ADDRESS Street, city, state, and zip
	APPLICANT'S NAME Name of the applicant	
	EXAMINER'S NAME Name of the examiner	DATE Date of filing

U.S. PATENT DOCUMENTS							
EXAMINED INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	OFF- CLASS	EXAMINER
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FOREIGN PATENT DOCUMENTS							
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	AM						Ex- m
	AN						Ex- m
	AO						Ex- m
	AP						Ex- m
	AQ						Ex- m

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)			
2000	AP	—	International Search Report for Application No. 09/000,000, mailed July 11, 2000, containing 10 pages.
✓	AM	—	Machine-readable form of the International Search Report for Application No. 09/000,000, mailed July 11, 2000, containing 10 pages.
	AN		

EXAMINER'S NAME Name of the examiner	DATE Date of filing
---	------------------------